

8-input NAND gate

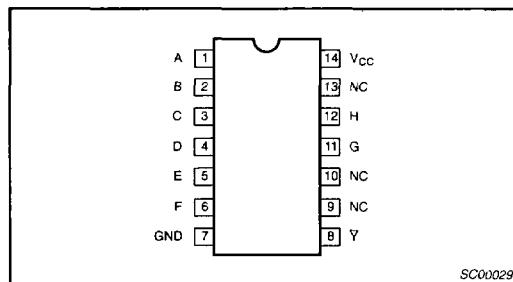
74ALS30A

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74ALS30A	5.0ns	0.5mA

ORDERING INFORMATION

DESCRIPTION	ORDER CODE	DRAWING NUMBER
	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$, $T_{amb} = 0^\circ C$ to $+70^\circ C$	
14-pin plastic DIP	74ALS30AN	SOT27-1
14-pin plastic SO	74ALS30AD	SOT108-1

PIN CONFIGURATION

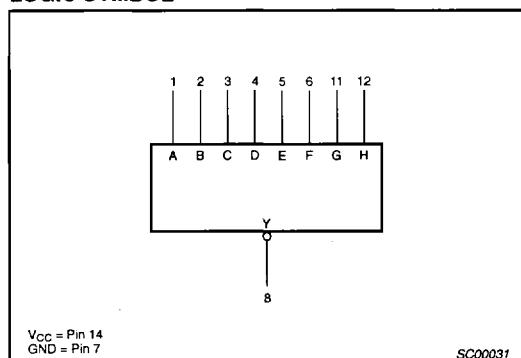


INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

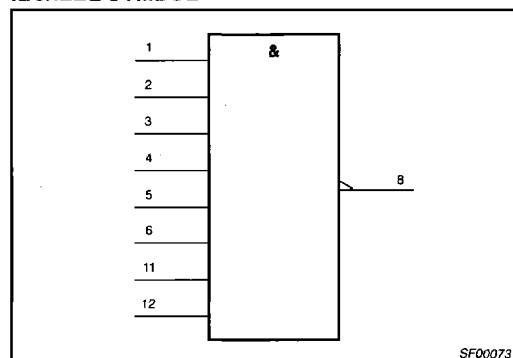
PINS	DESCRIPTION	74ALS (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
A - H	Data inputs	1.0/1.0	20µA/0.1mA
Y	Data output	20/80	0.4mA/8mA

NOTE: One (1.0) ALS unit load is defined as: 20µA in the High state and 0.1mA in the Low state.

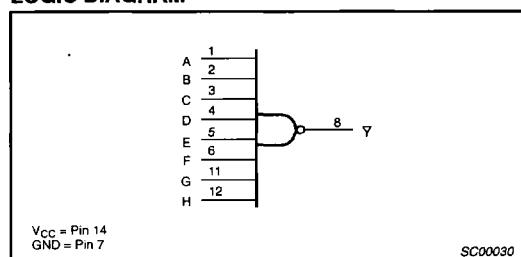
LOGIC SYMBOL



IEC/IEEE SYMBOL



LOGIC DIAGRAM



FUNCTION TABLE

A	B	C	D	E	F	G	H	INPUTS		OUTPUT
								X	X	
H	H	H	H	H	H	H	H	L		
L	X	X	X	X	X	X	X	X	X	H
X	L	X	X	X	X	X	X	X	X	H
X	X	L	X	X	X	X	X	X	X	H
X	X	X	L	X	X	X	X	X	X	H
X	X	X	X	L	X	X	X	X	X	H
X	X	X	X	X	L	X	X	X	X	H
X	X	X	X	X	X	L	X	X	X	H
X	X	X	X	X	X	X	L	X	X	H
X	X	X	X	X	X	X	X	L	X	H

H = High voltage level

L = Low voltage level

X = Don't care

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ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limit set forth in this table may impair the useful life of the device.
Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V_{CC}	Supply voltage	-0.5 to +7.0	V
V_{IN}	Input voltage	-0.5 to +7.0	V
I_{IN}	Input current	-30 to +5	mA
V_{OUT}	Voltage applied to output in High output state	-0.5 to V_{CC}	V
I_{OUT}	Current applied to output in Low output state	16	mA
T_{amb}	Operating free-air temperature range	0 to +70	°C
T_{stg}	Storage temperature range	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5.0	5.5	V
V_{IH}	High-level input voltage	2.0			V
V_{IL}	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			-18	mA
I_{OH}	High-level output current			-0.4	mA
I_{OL}	Low-level output current			8	mA
T_{amb}	Operating free-air temperature range	0		+70	°C

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS ¹	LIMITS			UNIT
			MIN	TYP ²	MAX	
V_{OH}	High-level output voltage	$V_{CC} \pm 10\%$, $V_{IL} = \text{MAX}$, $V_{IH} = \text{MIN}$, $I_{OH} = -0.4\text{mA}$	$V_{CC} - 2$			V
V_{OL}	Low-level output voltage	$V_{CC} = \text{MIN}$, $V_{IL} = \text{MAX}$, $V_{IH} = \text{MIN}$	$I_{OL} = 4\text{mA}$	0.25	0.40	V
			$I_{OL} = 8\text{mA}$	0.35	0.50	V
V_{IK}	Input clamp voltage	$V_{CC} = \text{MIN}$, $I_i = I_{IK}$		-0.73	-1.5	V
I_i	Input current at maximum input voltage	$V_{CC} = \text{MAX}$, $V_i = 7.0\text{V}$			0.1	mA
I_{IH}	High-level input current	$V_{CC} = \text{MAX}$, $V_i = 2.7\text{V}$			20	μA
I_{IL}	Low-level input current	$V_{CC} = \text{MAX}$, $V_i = 0.5\text{V}$			-0.1	mA
I_O	Output current ³	$V_{CC} = \text{MAX}$, $V_O = 2.25\text{V}$	-30		-112	mA
I_{CC}	Supply current (total)	I_{CCH}	$V_i = 0\text{V}$	0.20	0.36	mA
		I_{CCL}	$V_i = 4.5\text{V}$	0.64	0.9	mA

NOTES:

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at $V_{CC} = 5\text{V}$, $T_{amb} = 25^\circ\text{C}$.
- The output conditions have been chosen to produce a current that closely approximate one half of the true short-circuit output current, I_{OS} .

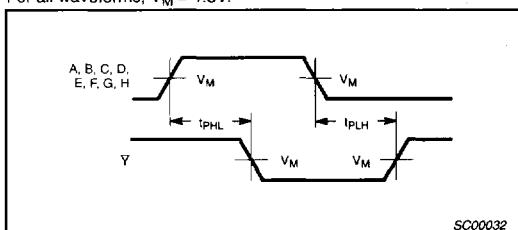
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AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS		UNIT	
			$T_{amb} = 0^\circ\text{C to } +70^\circ\text{C}$			
			$V_{CC} = +5.0V \pm 10\%$	$C_L = 50\text{pF}, R_L = 500\Omega$		
t_{PLH} t_{PHL}	Propagation delay A, B, C, D, E, F, G, H to $n\bar{Y}$	Waveform 1	2.0 3.0	8.0 10.0	ns	

AC WAVEFORMS

For all waveforms, $V_M = 1.3V$.

Waveform 1. Propagation Delay for Data to Output

TEST CIRCUIT AND WAVEFORMS

